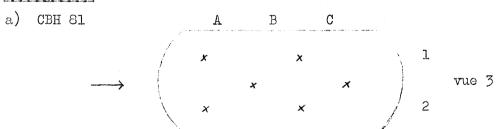
### Ieps-on-line

We hope to have part of the Ieps working on-line with some computer at the end of 1966. In the final system the computer will perform besides logical and geometrical checks, an automatic presentation and labelling of the event. For that, it makes use of the scan card information, especially of the event number, grid position, topology and coded comments. Therefore the measurement has to be prepared by delivering scan cards of the correct format (see: TC Program Library, section Utility-Index, C 001, will be revised with new format)

In order to minimize program space in the control computer, grids, labels and coded comments have to be standardized. To keep changes from the present system as little as possible, grids and labels of all running experiments were compared and the overlap is defined as standard.

#### 1. Coordinates



b) HBC 200. There is a similar coordinate system, going from A to J and from 1 to 5, but with opposite direction of 1 to 5 in the K<sup>+</sup> and the p experiment. These groups have to standardize their coordinate systems.

### 2. Labels

Primary interaction point A, A, C, D, E Beam particle (second label) ٦ Decay vertex of a Vo M, N, O,  $\mathbf{L}$ Decay vertex of a  $V^{\pm}$ P. Q. R, I Stopping point F, G, H, W Secondary interaction point S, T, U, Zero length track 7.

The label matrices of GRIND titles will have to be adjusted after starting on-line measurements.

# 3. Coded Comments

There will be 9 characters available for coded comments. They will modify the presentation of the labels. Their format is 3A3.

# Examples:

AlB Al is changed to Bl, with it all An to Bn

A2F A2 is changed to AF

M3S M3 is changed to MS

(S2 and S3 are not presented, but have to be typed in if wanted).

BCD comments have free format and are only typed out to the operator.

The revision of the scan card format will be done by G. Kellner and C. Letertre. All suggestions should be given to them.

A. Minten 26.2.1966

Distribution: All Physicists and Programmers of TC Division.

C. Verkerk, L. Tausch - DD Division.